

<b>Notice of References Cited</b>	Application/Control No. 10/549,638		Applicant(s)/Patent Under Reexamination TIEKE ET AL.	
	Examiner Michael V. Battaglia		Art Unit 2627	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0137909	07-2003	Ito et al.	369/47.14
*	B	US-2003/0063545	04-2003	Suzuki, Ryoichi	369/59.25
*	C	US-2004/0133739	07-2004	Sasaki, Yoshiyuki	711/112
*	D	US-2003/0048733	03-2003	Heemskerk et al.	369/94
*	E	US-5,778,257	07-1998	Tsukatani et al.	710/74
*	F	US-6,091,686	07-2000	Caffarelli et al.	369/53.24
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002170338 A	06-2002	Japan	YOSHIMURA et al.	
	O	JP 2000067511 A	03-2000	Japan	KAWASHIMA et al.	
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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